

Calculation of LFSR seed and polynomial pair for BIST applications [Electronic resource]

Jutman, Artur; Tšertov, Anton; Ubar, Raimund-Johannes 2008 IEEE Design and Diagnostics of Electronic Circuits and Systems : Bratislava, Slovakia, April 16-18, 2008 2008 / p. 275-279 : ill. [CD-ROM]

Code coverage analysis using high-level decision diagrams [Electronic resource]

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